





SCHS051J - NOVEMBER 1998 - REVISED AUGUST 2024

CD4066B CMOS Quad Bilateral Switch

1 Features

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- 15V digital or ±7.5V peak-to-peak switching
- 125Ω typical on-state resistance for 15V operation
- Switch on-state resistance matched to within 5Ω over 15V signal-input range
- On-state resistance flat over full peak-to-peak signal range
- High on or off output-voltage ratio: 80dB typical at f_{is} = 10kHz, R_L = 1k Ω
- High degree of linearity: <0.5% distortion typical at f_{is} = 1kHz, V_{is} = 5V_{p-p}
 - $V_{DD} V_{SS} \ge 10V, R_L = 10k\Omega$
- Extremely low off-state switch leakage, resulting in very low offset current and high effective off-state resistance: 10 pA typical at $V_{DD} V_{SS} = 10V$, $T_A = 25^{\circ}C$
- Extremely high control input impedance (control circuit isolated from signal circuit): 10¹²Ω typical
- Low crosstalk between switches: –50dB typical at $f_{is} = 8MHz$, $R_L = 1k\Omega$
- Matched control-input to signal-output capacitance: reduces output signal transients
- Frequency response, switch On = 40MHz typical
- 100% tested for quiescent current at 20V
- 5V, 10V, and 15V parametric ratings

2 Applications

- Analog signal switching and multiplexing: signal gating, modulators, squelch controls, demodulators, choppers, commutating switches
- Digital signal switching and multiplexing
- Analog-to-digital and digital-to-analog conversions
- Digital control of frequency, impedance, phase, and analog-signal gain
- Building automation

3 Description

The CD4066B device is a quad bilateral switch intended for the transmission or multiplexing of analog or digital signals. It is pin-for-pin compatible with the CD4016B device, but exhibits a much lower onstate resistance. In addition, the on-state resistance is relatively constant over the full signal-input range.

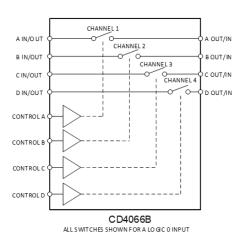
The CD4066B device consists of four bilateral switches, each with independent controls. Wide operating supply of 3V to 18V allows for use in a broad array of applications. The advantages over single-channel switches include peak input-signal voltage swings equal to the full supply voltage and more constant on-state impedance over the input-signal range. However, for sample-and-hold applications, the CD4016B device is recommended.

Package	Information
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r dokugo information				
PART NUMBER	PACKAGE ⁽¹⁾	PACKAGE SIZE ⁽²⁾		
CD4066B	N (PDIP, 14)	19.3mm × 9.4mm		
	D (SOIC, 14)	8.65mm × 6mm		
	NS (SOP, 14)	10.2mm × 7.8mm		
	PW (TSSOP, 14)	5mm × 6.4mm		

(1) For more information, see Section 11

(2) The package size (length × width) is a nominal value and includes pins, where applicable.



Bidirectional Signal Transmission Through Digital Control Logic



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4 Pin Configuration and Functions

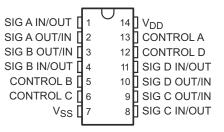


Figure 4-1. N, J, D, NS, or PW Packages 14-Pin PDIP, CDIP, SOIC, SOP, or TSSOP (Top View)

PIN		TYPE ⁽¹⁾	DESCRIPTION
NAME	NO.		DESCRIPTION
SIG A IN/OUT	1	I/O	Input/Output for Switch A
SIG A OUT/IN	2	I/O	Output/Input for Switch A
SIG B OUT/IN	3	I/O	Output/Input for Switch B
SIG B IN/OUT	4	I/O	Input/Output for Switch B
CONTROL B	5	I	Control pin for Switch B
CONTROL C	6	I	Control pin for Switch C
V _{SS}	7	—	Low Voltage Power Pin
SIG C IN/OUT	8	I/O	Input/Output for Switch C
SIG C OUT/IN	9	I/O	Output/Input for Switch C
SIG D OUT/IN	10	I/O	Output/Input for Switch D
SIG D IN/OUT	11	I/O	Input/Output for Switch D
CONTROL D	12	I	Control Pin for D
CONTROL A	13	I	Control Pin for A
V _{DD}	14	_	Power Pin

Table 4-1. Pin Functions

(1) I = input, O = output



5 Specifications

5.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)⁽¹⁾ (2)

		MIN	MAX	UNIT
$V_{DD} - V_{SS}$			20	V
V _{DD}	Supply voltage	-0.5	20	V
V _{SS}		-20	0.5	V
I _{SEL} or I _{EN}	Logic control input pin current (EN, Ax, SELx)	-30	30	mA
V_{S} or V_{D}	Source or drain voltage (Sx, D)	V _{SS} –0.5	V _{DD} +0.5	V
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, D)	-20	20	mA
TJ	Junction temperature		150	°C
T _{stg}	Storage temperature	-65	150	°C

(1) Stresses beyond those listed under Absolute Maximum Rating may cause permanent damage to the device. These are stress ratings only, which do not imply functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Condition. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltages are with respect to ground, unless otherwise specified.

5.2 ESD Ratings

			VALUE	UNIT
V _(ESD) Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001, all pins ⁽¹⁾	±500	V	
V (ESD)	LICCU OSIANO UISCHAIGE	Charged device model (CDM), per JEDEC specification JESD22-C101, all $\ensuremath{pins}^{(2)}$	±1500	v

(1) JEDEC document JEP155 states that 500V HBM allows safe manufacturing with a standard ESD control process.

(2) JEDEC document JEP157 states that 250V CDM allows safe manufacturing with a standard ESD control process.

5.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
$V_{DD} - V_{SS}^{(1)}$	Power supply voltage differential	3	18	V
V _{DD}	Positive power supply voltage	3	18	V
$V_{S} \text{ or } V_{D}$	Signal path input/output voltage (source or drain pin) (Sx, D)	V _{SS}	V _{DD}	V
V_{SEL} or V_{EN}	Address or enable pin voltage	0	V _{DD}	V
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, D)	-10	10	mA
T _A	Ambient temperature	-55	125	°C

(1) V_{DD} and V_{SS} can be any value as long as $3V \le (V_{DD} - V_{SS}) \le 24V$, and the minimum V_{DD} is met.



5.4 Thermal Information

			CD4	406x		
THERMAL METRIC ⁽¹⁾		N (PDIP)	D (SOIC)	NS (SO)	PW (TSSOP)	UNIT
		14 PINS	14 PINS	14 PINS	14 PINS	
R _{θJA}	Junction-to-ambient thermal resistance	93.7	109.7	112.4	101.8	°C/W
R _{0JC(top)}	Junction-to-case (top) thermal resistance	72.5	69.4	70.4	44.3	°C/W
R _{θJB}	Junction-to-board thermal resistance	68.0	67.9	76.4	68.2	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	50.3	25.8	28.9	3.2	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	67.3	67.1	75.4	67.6	°C/W

(1) For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

5.5 Electrical Characteristics

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5V$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

	PARAMET	ER		TEST CONDITIONS	MIN	TYP MAX	UNI T
SIGN	AL INPUTS (VIS) AND	OUTPUTS (V _{OS})					
			V _{DD} = 5V V _{is} = 0V			0.4	V
Vos			V _{DD} = 5V V _{is} = 5V		4.6		V
			V _{DD} = 10V V _{is} = 0V			0.5	V
	Switch output voltage		V _{DD} = 10V V _{is} = 10V		9.5		V
			V _{DD} = 15V V _{is} = 0V			1.5	V
			V _{DD} = 15V V _{is} = 15V		13.5		V
	On-state resistance di any two switches	ifference between		V _{DD} = 5V		15	
Δ R _{ON}	$\begin{tabular}{ c c c c }\hline \hline & & & & & \\ \hline & & & & \\ \hline & & & & \\ \hline & & & &$	V _{DD} = 10V		10	Ω		
		V _{DD} = 15V		5			
		1		V _{DD} = 5V	3.5		V
V _{IHC}	Control input, high vol	Itage	See Figure 7	V _{DD} = 10V	7		V
				V _{DD} = 15V	11		V
			$V_{IN} = V_{DD}, C_L =$	V _{DD} = 5V		6	
			50pF, R _L = 1kΩ V _C = 10V (square	V _{DD} = 10V		9	
	Maximum control inpu			V _{DD} = 15V		9.5	MHz

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5.5 Electrical Characteristics (continued)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5V$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

	PARAMETER		TEST CONDITIONS	MIN TYP MAX	UNI T
C _{IN}	Input Capacitance			5 7.5	pF
			T _A = -55°C	0.64	
			$T_A = -40^{\circ}C$	0.61]
		$V_{DD} = 5V$ $V_{is} = 0V$	T _A = 25°C	0.51	mA
		15 - 1	T _A = 85°C	0.42	
		T _A = 125°C	0.36]	
			T _A = -55°C	-0.64	
		$T_A = -40^{\circ}C$	-0.61]	
	V _{DD} = 5V V _{is} = 5V	T _A = 25°C	-0.51	mA	
		T _A = 85°C	-0.42]	
		T _A = 125°C	-0.36	1	
		T _A = -55°C	1.6	4	
		$T_A = -40^{\circ}C$	1.5		
	$V_{DD} = 10V$ $V_{is} = 0V$	T _A = 25°C	1.3		
			T _A = 85°C	1.1	-
	Switch input current		T _A = 125°C	0.9	
S	Switch input current		T _A = -55°C	-1.6	mA
			$T_A = -40^{\circ}C$	-1.5	
		V _{DD} = 10V V _{is} = 10V	T _A = 25°C	-1.3	
		VIS TOV	T _A = 85°C	-1.1	
			T _A = 125°C	-0.9	
			T _A = -55°C	4.2	
			$T_A = -40^{\circ}C$	4	
		V _{DD} = 15V V _{is} = 0V	T _A = 25°C	3.4	mA
		VIS OV	T _A = 85°C	2.8	1
			T _A = 125°C	2.4	1
			T _A = -55°C	-4.2	
			$T_A = -40^{\circ}C$	-4	1
		V _{DD} = 15V V _{is} = 15V	T _A = 25°C	-3.4	mA
		v _{IS} = 15v	T _A = 85°C	-2.8	1
			T _A = 125°C	-2.4	1
					1



5.5 Electrical Characteristics (continued)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5V$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER		TEST COND	ITIONS	MIN TYP MAX	(^L
		T _A = -55°C		5	5
		T _A = -40°C		Ę	5
	$V_{is} = 0 \text{ to } 5V$ $V_{DD} = 5V$	T _A = 25°C		4 6	3
		T _A = 85°C		7	7
		T _A = 125°C		7.5	5
		T _A = -55°C		6	3
UDD Quiescent Device Current All switches OFF		T _A = -40°C		6	3
	V _{is} = 0 to 10V V _{DD} = 10V	T _A = 25°C		5 7	7
		T _A = 85°C		8	3
		T _A = 125°C		9	9
		T _A = –55°C		7	7
		T _A = -40°C		7.5	5
	V _{is} = 0 to 15V V _{DD} = 15V	T _A = 25°C		5.5 8	3
	VDD - 13V	T _A = 85°C		9)
		T _A = 125°C		1()
		T _A = -55°C		8.5	5
		T _A = -40°C		8.5	5
	$V_{is} = 0 \text{ to } 20V$ $V_{DD} = 20V$	T _A = 25°C		6.5 9)
	VDD - 20V	T _A = 85°C		10)
		T _A = 125°C		11	I
			T _A = -55°C	800)
			T _A = -40°C	850)
		V _{DD} = 5V	T _A = 25°C	470 1050)
			T _A = 85°C	1200)
			T _A = 125°C	1300)
			T _A = -55°C	310)
	to (V _{DD} +V _{SS})/2 ,V _C		T _A = -40°C	330)
N ON Resistance r _{ON} Max	$= V_{DD}, R_L = 10 k\Omega$	V _{DD} = 10V	T _A = 25°C	180 400)
	returned $V_{is} = V_{SS}$ to V_{DD}		T _A = 85°C	500)
			T _A = 125°C	500)
			T _A = -55°C	200)
			T _A = -40°C	210)
		V _{DD} = 15V	T _A = 25°C	125 240)
			T _A = 85°C	300)
			T _A = 125°C	320)



5.5 Electrical Characteristics (continued)

Over operating free-air temperature range, $V_{SUPPLY} = \pm 5V$, and $R_L = 100 \Omega$, (unless otherwise noted)⁽¹⁾

PARAMETER			TEST CONDITIONS			MIN	ТҮР	МАХ	UNI T		
					T _A = -55°C		1				
					$T_A = -40^{\circ}C$		1				
				V _{DD} = 5V	T _A = 25°C		1				
					T _A = 85°C		1				
					T _A = 125°C		1		1		
					T _A = -55°C		1				
			I _{is} < 10 μA, V _{is} =		T _A = -40°C	1					
VILC	Control input, low voltage	ge (max)	$V_{SS}, V_{OS} = V_{DD},$ and $V_{is} = V_{DD},$	V _{DD} = 10V	T _A = 25°C		1		V		
			$V_{OS} = V_{SS}$		T _A = 85°C		1		-		
					T _A = 125°C		1				
					T _A = -55°C		1		1		
					T _A =40°C		1				
				V _{DD} = 15V	T _A = 25°C		1				
					T _A = 85°C		1				
					T _A = 125°C		1				
	Input current (max)			T _A = -55°C		-0.8		0.8			
				T _A =40°C		-0.8		0.8			
			$V_{is} \le V_{DD}, V_{DD} - V_{SS} = 18V, V_{CC} \le$	T _A = 25°C		-0.7	±0.2	0.7			
I _{IN}	Input current (max)	Input current (max)	$\begin{vmatrix} V_{DD} - V_{SS} & V_{DD} = \\ 18V \end{vmatrix}$	T _A = 85°C		-0.6		0.6	μA		
	Input current (max) Input current (max)			T _A = 125°C		-0.55		0.55			

(1) Peak-to-Peak voltage symmetrical about $(V_{DD} - V_{EE}) / 2$.

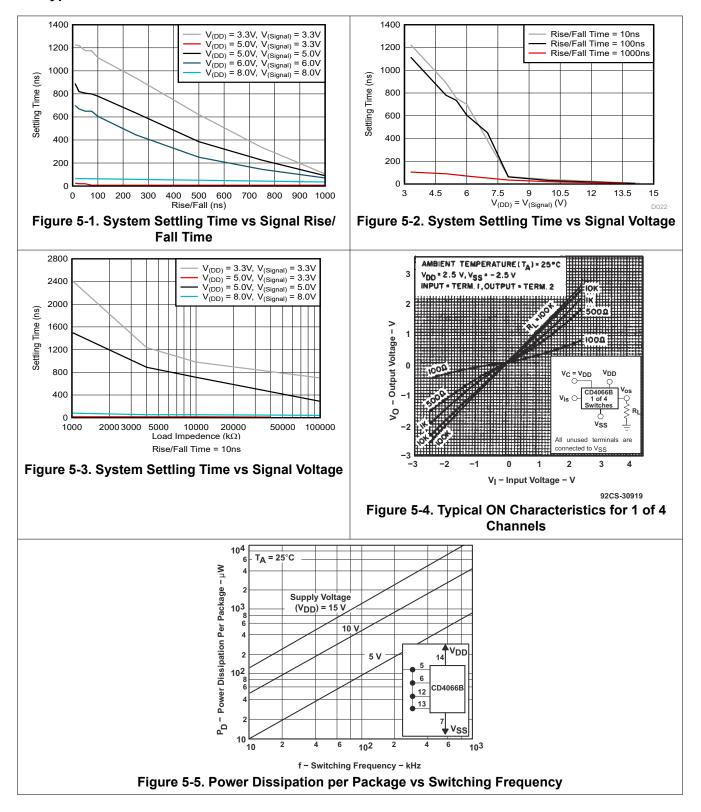
5.6 Switching Characteristics

T_A = 25°C

PARAMETER	FROM	то	TEST CONDITIONS	V _{cc}	MIN	TYP	MAX	UNIT
	Signal input		$V_{IN} = V_{DD}$, t_r , $t_f = 20$ ns, $C_L = 50$ pF, $R_L = 1$ k Ω	5V		20	40	
t _{pd}				10V		10	20	ns
				15V		7	15	
		Signal output	$V_{IN} = V_{DD}$, t_r , $t_f = 20$ ns, $C_L = 50$ pF, $R_L = 1$ k Ω	5V		35	70	
t _{plh}	Signal input			10V		20	40	ns
				15V		15	30	
		Signal output	$V_{IN} = V_{DD}, t_r, t_f = 20$ ns, C _L = 50pF, R _L = 1kΩ	5V		35	70	
t _{phl}	Signal input			10V		20	40	ns
				15V		15	30	

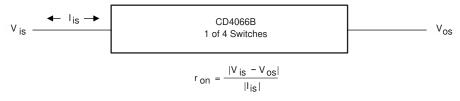


5.7 Typical Characteristics





6 Parameter Measurement Information



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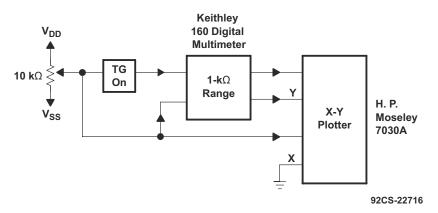


Figure 6-2. Channel On-State Resistance Measurement Circuit

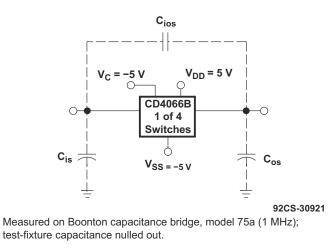
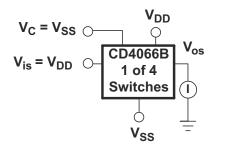


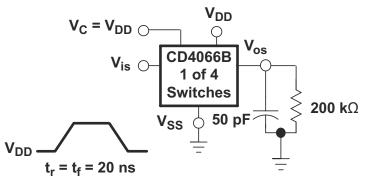
Figure 6-3. Typical On Characteristics for One of Four Channels



92CS-30922

All unused terminals are connected to V_{SS}.

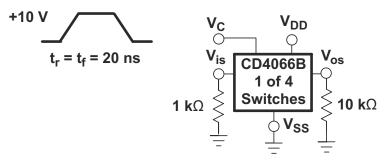
Figure 6-4. Off-Switch Input or Output Leakage



92CS-30923

All unused terminals are connected to V_{SS}.

Figure 6-5. Propagation Delay Time Signal Input (Vis) to Signal Output (Vos)

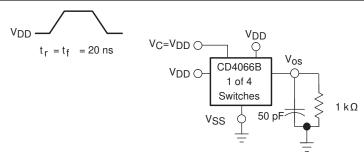


92CS-30924

All unused terminals are connected to V_{SS}.

Figure 6-6. Crosstalk-Control Input to Signal Output



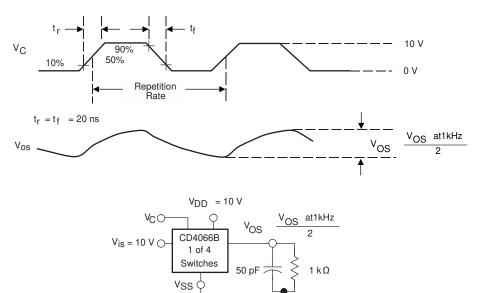


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All unused pins are connected to $\mathsf{V}_{\mathsf{SS}}.$

Delay is measured at V_{os} level of +10% from ground (turn-on) or on-state output level (turn-off).

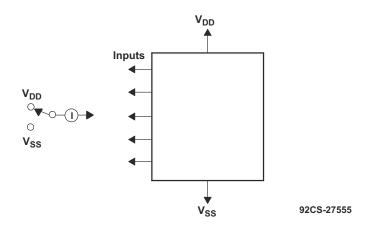
Figure 6-7. Propagation Delay, t_{PLH}, t_{PHL} Control-Signal Output



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All unused pins are connected to V_{SS} .

Figure 6-8. Maximum Allowable Control-Input Repetition Rate

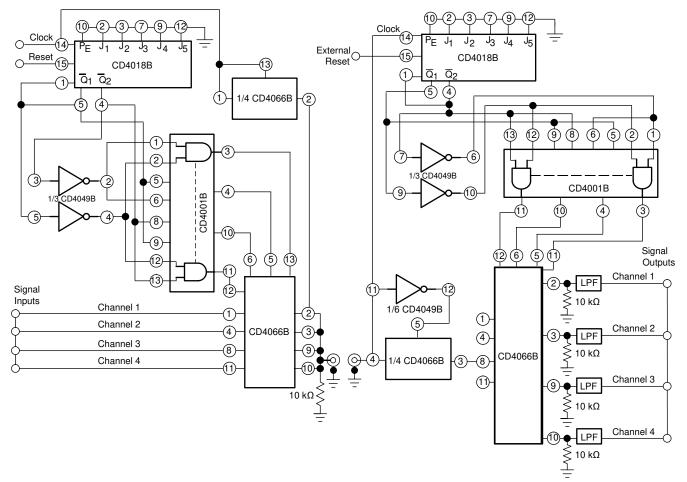


Measure inputs sequentially to both V_{DD} and V_{SS} . Connect all unused inputs to either V_{DD} or V_{SS} . Measure control inputs only.

Figure 6-9. Input Leakage-Current Test Circuit



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Figure 6-10. Four-Channel PAM Multiplex System Diagram

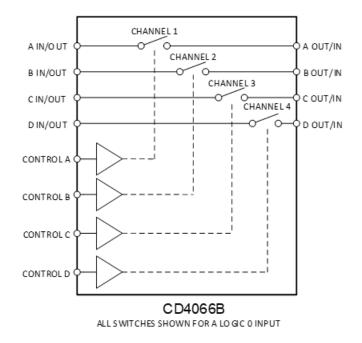


7 Detailed Description

7.1 Overview

CD4066B has four independent digitally controlled analog switches with a bias voltage of V_{SS} to allow for different voltage levels to be used for low output. Both the p and n devices in a given switch are biased on or off simultaneously by the control signal. As shown in Figure 7-1, the well of the n-channel device on each switch is tied to either the input (when the switch is on) or to V_{SS} (when the switch is off). Thus, when the control of the device is low, the output of the switch goes to V_{SS} and when the control is high the output of the device goes to V_{DD} .

7.2 Functional Block Diagram



- A. All control inputs are protected by the CMOS protection network.
- B. All p substrates are connected to V_{DD}.
- C. Normal operation control-line biasing: switch on (logic 1), $V_C = V_{DD}$; switch off (logic 0), $V_C = V_{SS}$.
- D. Signal-level range: $V_{SS} \le V_{is} \le V_{DD}$.

Figure 7-1. Schematic Diagram of One-of-Four Identical Switches and Associated Control Circuitry

7.3 Feature Description

Each switch has different control pins, which allows for more options for the outputs. Bias Voltage allows the device to output a voltage other than 0V when the device control is low. The CD4066B has a large absolute maximum voltage for V_{DD} of 20V.



7.4 Device Functional Modes

Table 7-1 lists the functions of this device.

INP	OUTPUT			
SIG IN/OUT	CONTROL	SIG OUT/IN		
Н	н	Н		
L	н	L		
X	L	Hi-Z		



8 Application and Implementation

Note

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

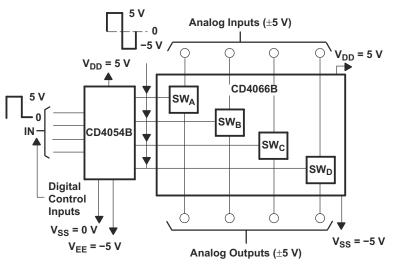
8.1 Application Information

In applications that employ separate power sources to drive V_{DD} and the signal inputs, the V_{DD} current capability should exceed V_{DD}/R_L (R_L = effective external load of the four CD4066B device bilateral switches). This provision avoids any permanent current flow or clamp action on the V_{DD} supply when power is applied or removed from the CD4066B device.

In certain applications, the external load-resistor current can include both V_{DD} and signal-line components. To avoid drawing V_{DD} current when switch current flows into pins 1, 4, 8, or 11, the voltage drop across the bidirectional switch must not exceed 0.8V (calculated from r_{on} values shown).

No V_{DD} current flows through R_L if the switch current flows into pins 2, 3, 9, or 10.

8.2 Typical Application



92CS-30927



8.2.1 Design Requirements

This device uses CMOS technology and has balanced output drive. Avoid bus contention because it can drive currents in excess of maximum limits. The high drive also creates fast edges into light loads, so consider routing and load conditions to prevent ringing.

8.2.2 Detailed Design Procedure

- 1. Recommended input conditions:
 - For rise time and fall time specifications, see Δt/Δv in *Recommended Operating Conditions*.
 - For specified high and low levels, see V_{IH} and V_{IL} in *Recommended Operating Conditions*.
- 2. Recommended output conditions:
 - Load currents should not exceed ±10mA.



8.2.3 Application Curve

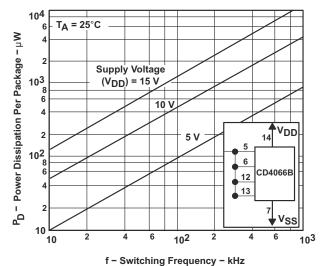


Figure 8-2. Power Dissipation vs. Switching Frequency

8.3 Power Supply Recommendations

The power supply can be any voltage between the MIN and MAX supply voltage rating located in *Recommended Operating Conditions*.

Each VCC pin should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, 0.1μ F is recommended; if there are multiple VCC pins, then 0.01μ F or 0.022μ F is recommended for each power pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. A 0.1μ F and a 1μ F are commonly used in parallel. The bypass capacitor should be installed as close to the power pin as possible for best results.

8.4 Layout

8.4.1 Layout Guidelines

When using multiple bit logic devices inputs must never float.

In many cases, functions or parts of functions of digital logic devices are unused, for example, when only two inputs of a triple-input *and* gate are used or only 3 of the 4 buffer gates are used. Such input pins must not be left unconnected because the undefined voltages at the outside connections result in undefined operational states. All unused inputs of digital logic devices must be connected to a high or low bias to prevent them from floating. The logic level that should be applied to any particular unused input depends on the function of the device. Generally they are tied to GND or VCC, whichever makes more sense or is more convenient. It is generally acceptable to float outputs, unless the part is a transceiver. If the transceiver has an output enable pin, it disables the output section of the part when asserted. This does not disable the input section of the I/Os, so they cannot float when disabled.

8.4.2 Layout Example

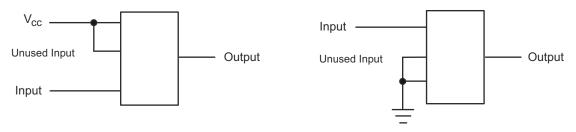


Figure 8-3. Diagram for Unused Inputs



9 Device and Documentation Support

9.1 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. Click on *Notifications* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

9.2 Support Resources

TI E2E[™] support forums are an engineer's go-to source for fast, verified answers and design help — straight from the experts. Search existing answers or ask your own question to get the quick design help you need.

Linked content is provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

9.3 Trademarks

TI E2E[™] is a trademark of Texas Instruments.

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9.4 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

9.5 Glossary

TI Glossary This glossary lists and explains terms, acronyms, and definitions.

10 Revision History

NOTE: Page numbers for previous revisions may differ from page numbers in the current version.

С	Changes from Revision I (May 2024) to Revision J (August 2024)						
•	Added Settling Time plots	9					

Changes from Revision H (January 2020) to Revision I (May 2024)						
•	Changed Package Information table to include package leads	1				
•	Changed the numbering format for tables, figures, and cross-references throughout the document	1				
	Deleted the J (CDIP, 14) package from the data sheet					
	Changed max and typ IDD for lower supply voltages					
	Changed VIL from 2V to 1V acorss supply					

С	hanges from Revision G (June 2017) to Revision H (January 2020)	Page
•	Added Junction Temperature details to the Absolute Maximum Ratings table	4

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.



PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CD4066BE	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD4066BE	Samples
CD4066BEE4	ACTIVE	PDIP	N	14	25	RoHS & Green	NIPDAU	N / A for Pkg Type	-55 to 125	CD4066BE	Samples
CD4066BF	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD4066BF	Samples
CD4066BF3A	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	CD4066BF3A	Samples
CD4066BM	OBSOLETE	SOIC	D	14		TBD	Call TI	Call TI	-55 to 125	CD4066BM	
CD4066BM96	ACTIVE	SOIC	D	14	2500	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	CD4066BM	Samples
CD4066BMT	OBSOLETE	SOIC	D	14		TBD	Call TI	Call TI	-55 to 125	CD4066BM	
CD4066BNS	OBSOLETE	SO	NS	14		TBD	Call TI	Call TI		CD4066B	
CD4066BNSR	ACTIVE	SO	NS	14	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD4066B	Samples
CD4066BPW	OBSOLETE	TSSOP	PW	14		TBD	Call TI	Call TI	-55 to 125	CM066B	
CD4066BPWR	ACTIVE	TSSOP	PW	14	2000	RoHS & Green	NIPDAU SN	Level-1-260C-UNLIM	-55 to 125	CM066B	Samples
JM38510/05852BCA	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	JM38510/ 05852BCA	Samples
M38510/05852BCA	ACTIVE	CDIP	J	14	25	Non-RoHS & Green	SNPB	N / A for Pkg Type	-55 to 125	JM38510/ 05852BCA	Samples

⁽¹⁾ The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

⁽²⁾ **RoHS**: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.



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PACKAGE OPTION ADDENDUM

⁽³⁾ MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

⁽⁴⁾ There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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OTHER QUALIFIED VERSIONS OF CD4066B, CD4066B-MIL :

• Catalog : CD4066B

• Automotive : CD4066B-Q1, CD4066B-Q1

Military : CD4066B-MIL

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Automotive Q100 devices qualified for high-reliability automotive applications targeting zero defects
- Military QML certified for Military and Defense Applications

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